



A Novel Method to Determine Amorphous Phase Concentrations Using the Rietveld Refinement Technique

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LAREC (Laboratorio Refinamiento Estructuras Cristalinas)

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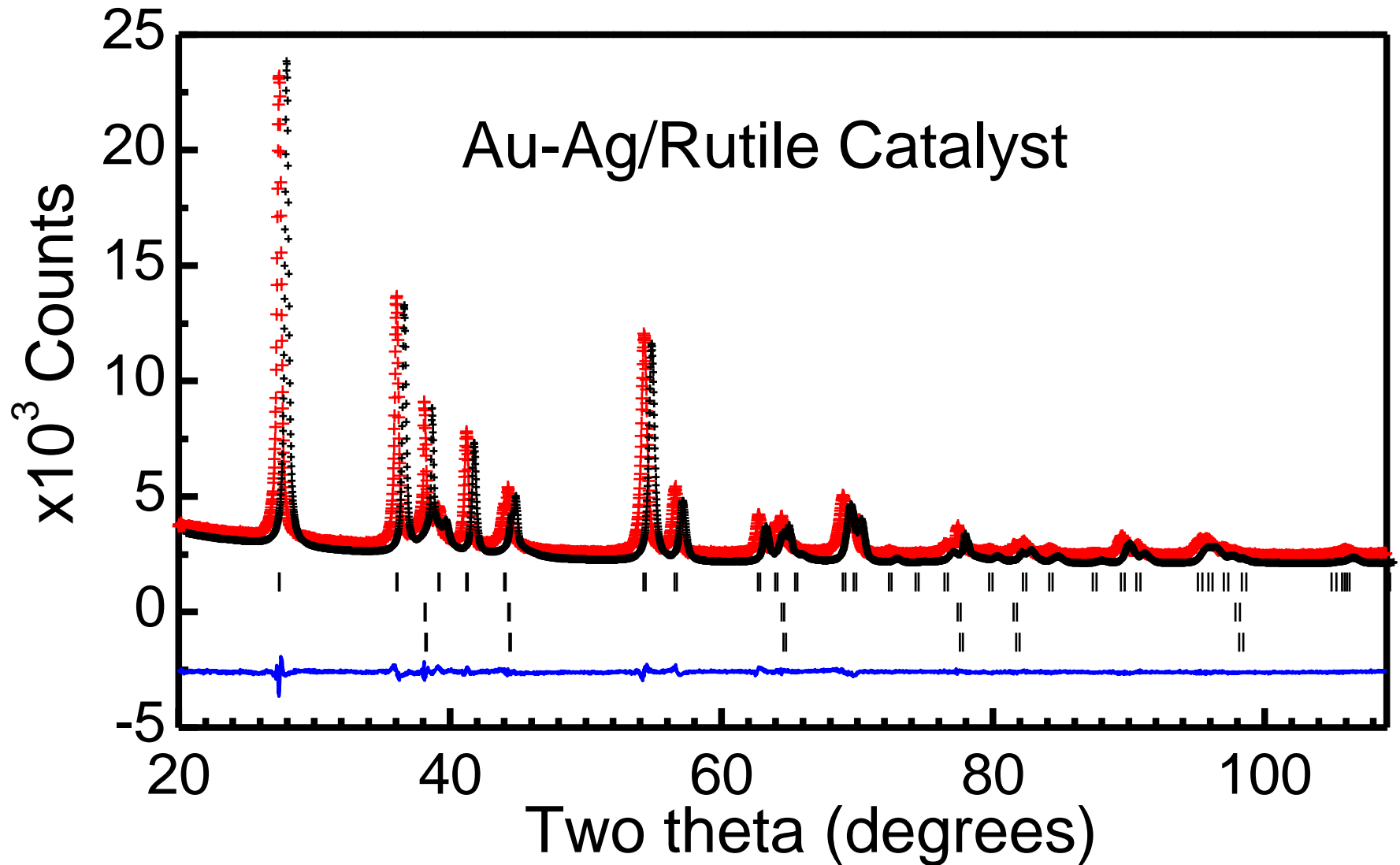
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$$y_{ci}(2\theta_i) = S \sum |F_K|^2 \phi(2\theta_i - 2\theta_K) L_K P_K A + y_{bi}$$

1. Structure factor, F_K : Crystallography
2. Phase Scale, S : Phase concentration
3. ϕ Sample Microstructure
and instrument: optics, L , A
4. Background, y_b :

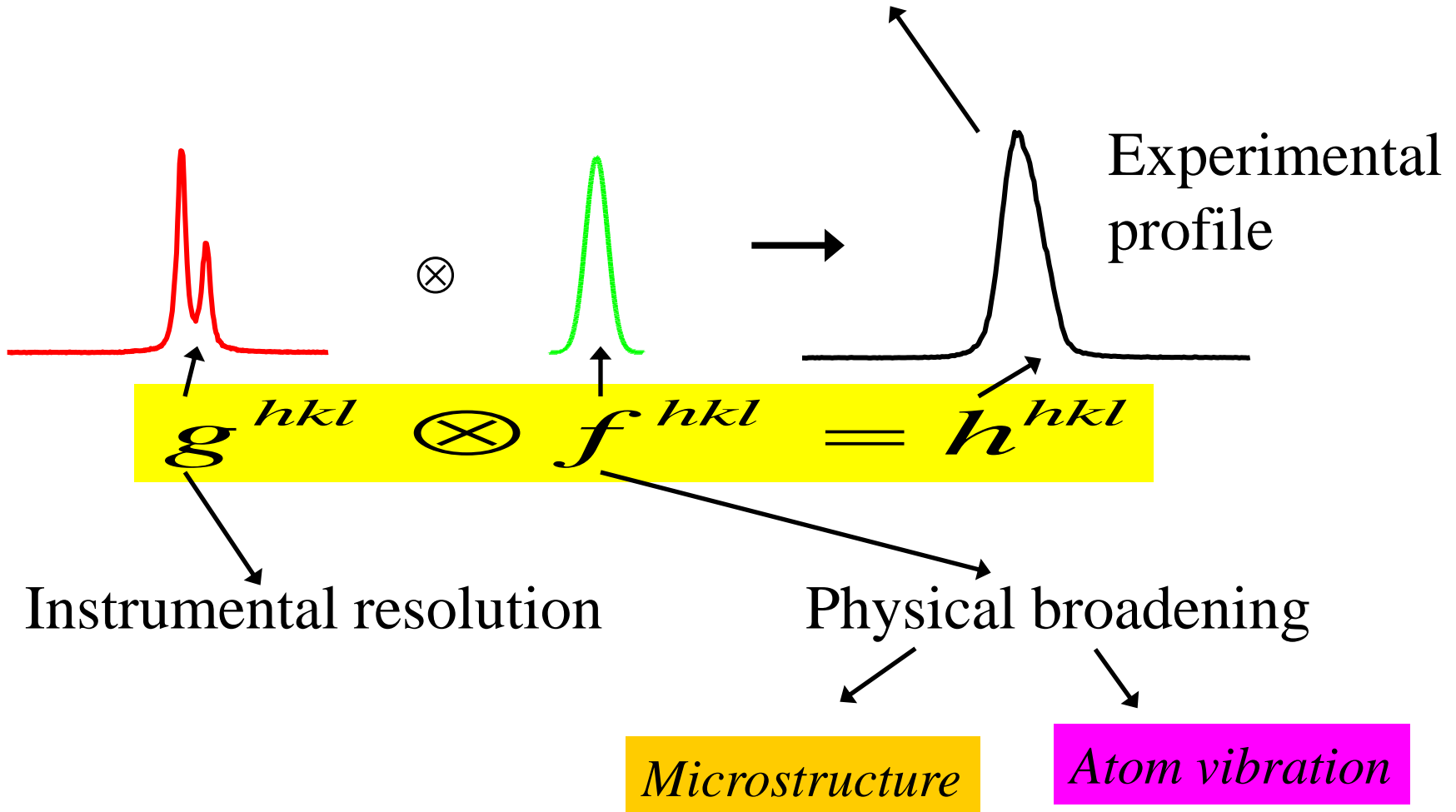


$$S_y = \sum w_i (y_i - y_{ci})^2; \quad w_i = 1/y_i$$





$$y_{ci}(2\theta_i) = s \sum |F_K|^2 \phi(2\theta_i - 2\theta_K) L_K P_K A + y_{bi}$$



Line Broadening



Peak diffraction profile $\phi(2\theta_K)$

Convolution of

Instrumental Function ($F_{\text{instrument}}$)

and Sample Function (F_{sample})

$$\phi(2\theta_K) = F_{\text{instrument}} \otimes F_{\text{sample}}$$

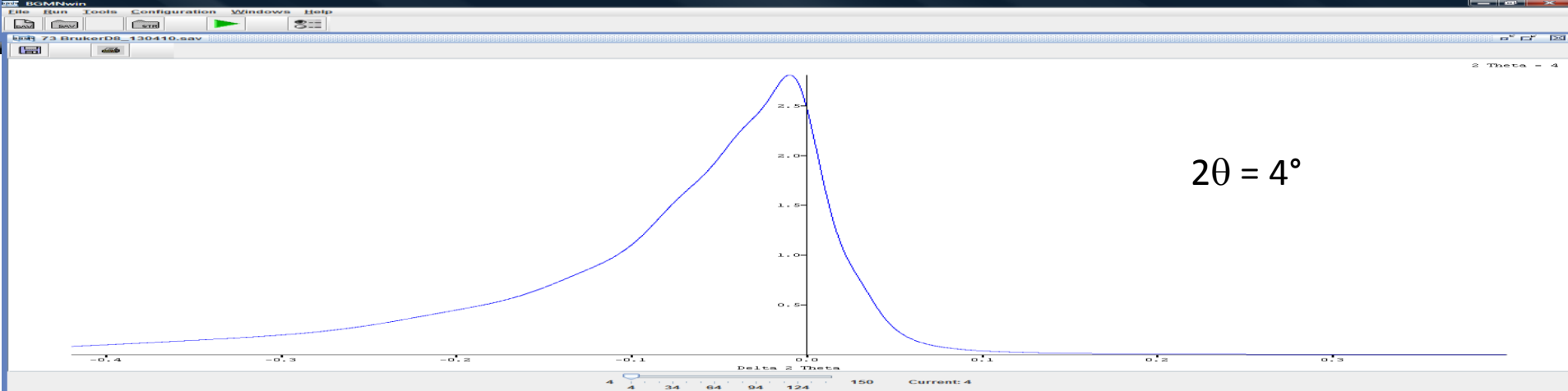
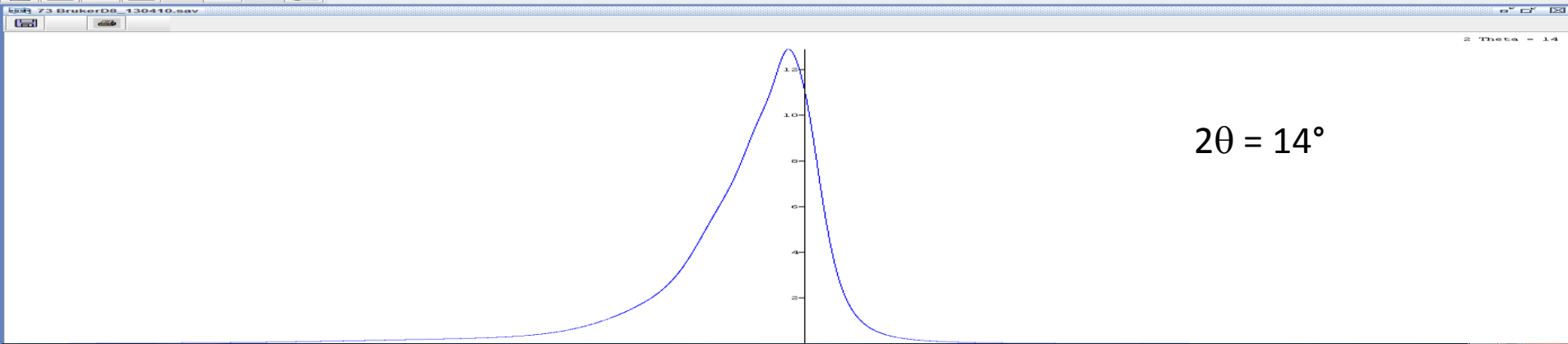
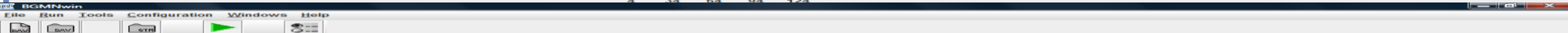
Instrumental function

$F_{\text{instrument}}$

-0.4°

$2\theta = 83^\circ$

$+0.4^\circ$





Sample function: F_{sample}

$$F_{\text{sample}} = F_{\text{crystallite size}} \otimes F_{\text{microstrain}} \otimes F_{\text{size_distribution}}$$

Crystallite size (Domain coherence)

Debye-Scherrer \Rightarrow **fw hm \propto $1/\text{Cos } \theta$**

Microstrain \Rightarrow **fw hm \propto $\text{Tan } \theta$**

Crystallite size distribution

Log-normal distribution: the logarithm of the crystallite size distribution follow a Gaussian distribution \Rightarrow **fw hm \propto σ ; (independent of θ)**



Scale factor -> Phase concentration

$$W_i (\%) = S_i (ZMV)_i / \sum_p S_p (ZMV)_p$$

W_i weight percent of phase i

S_i Phase scale factor

ZM Unit cell mass

V Unit cell volume



Au-Ag-Rutile Composite

Intensity (a. u.)

94.4 wt %
Rutile

Sample

3.6 wt %
Gold

2.0 wt %
Silver

Background

20

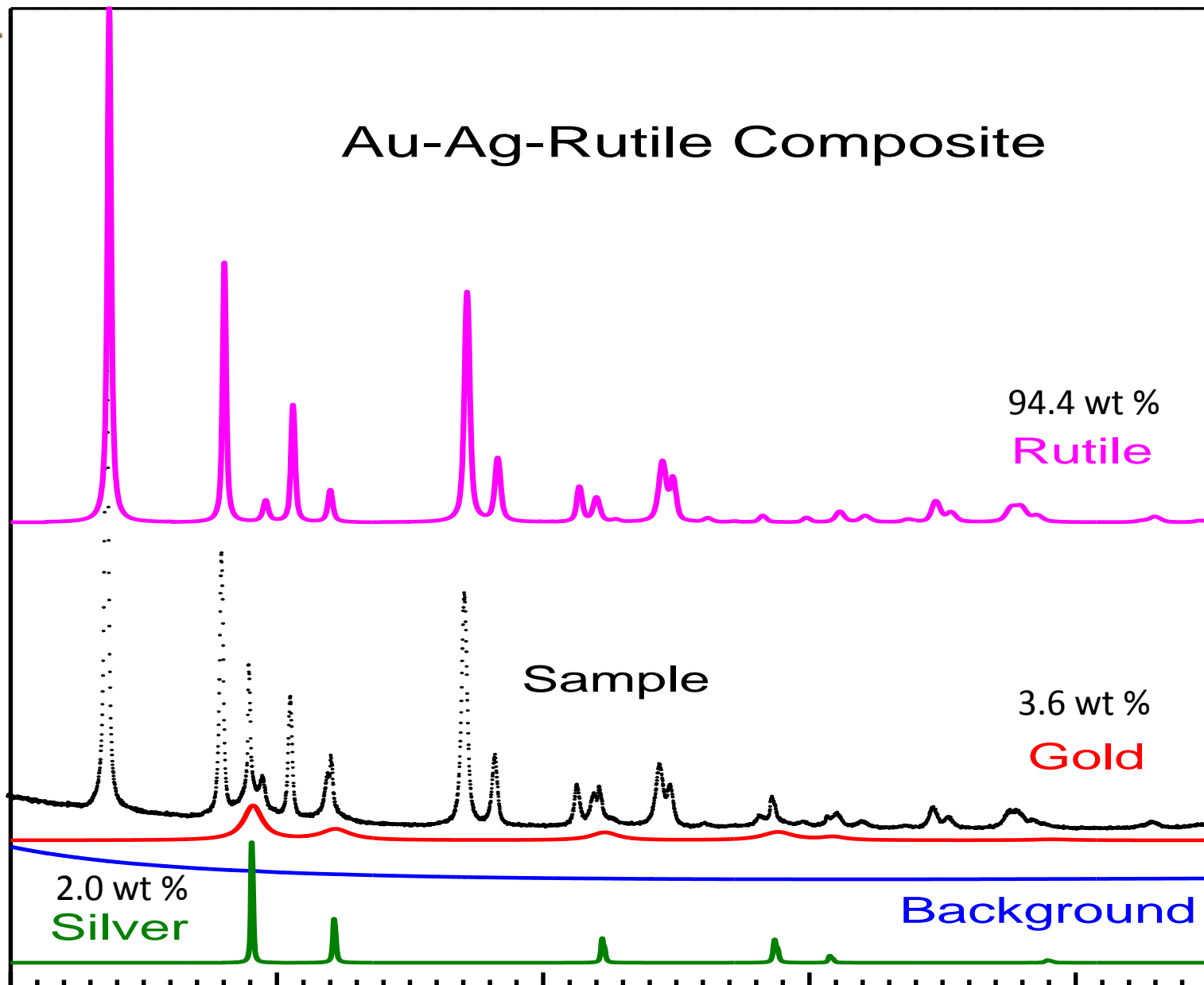
40

60

80

100

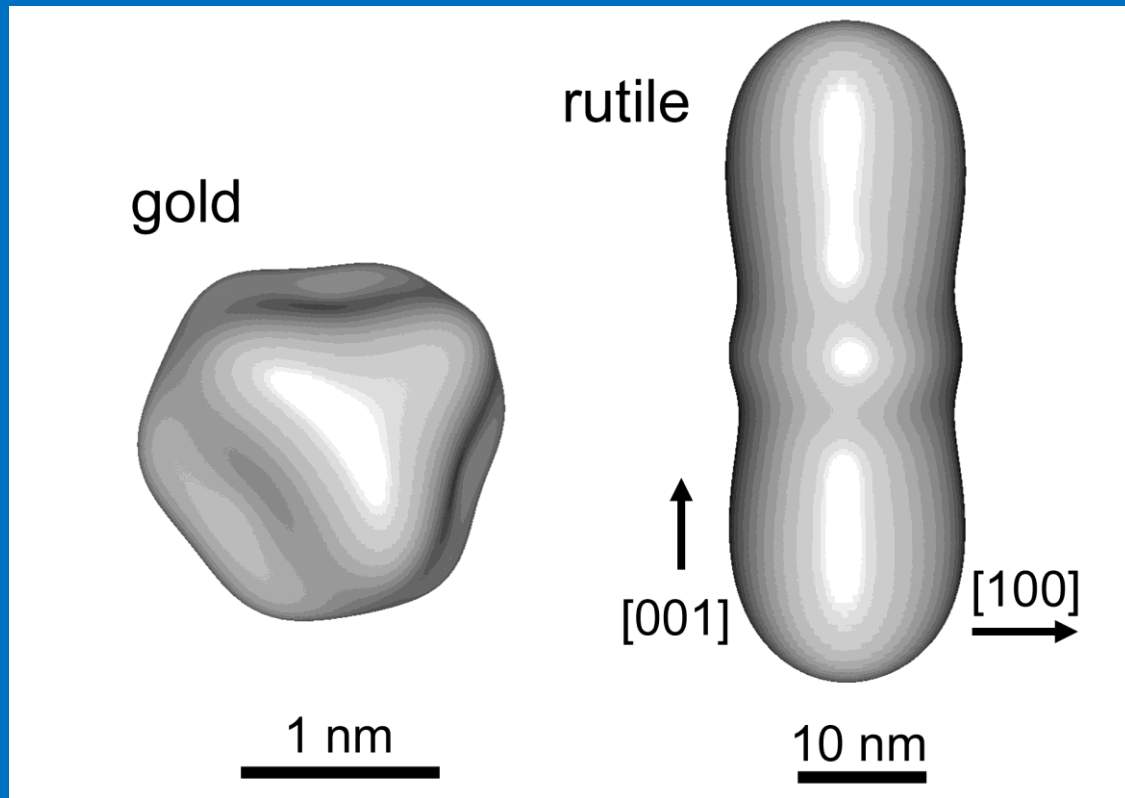
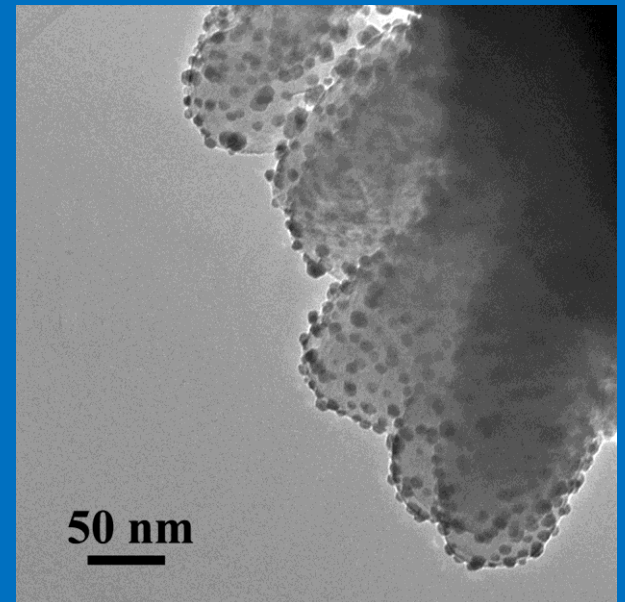
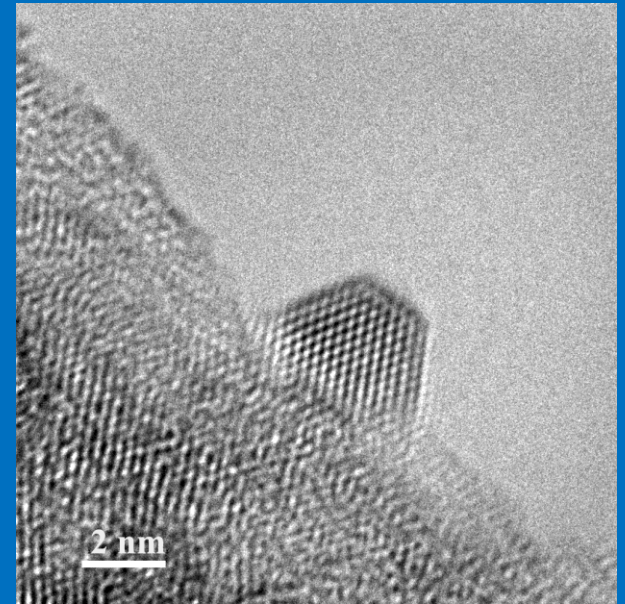
Two Theta (degrees)

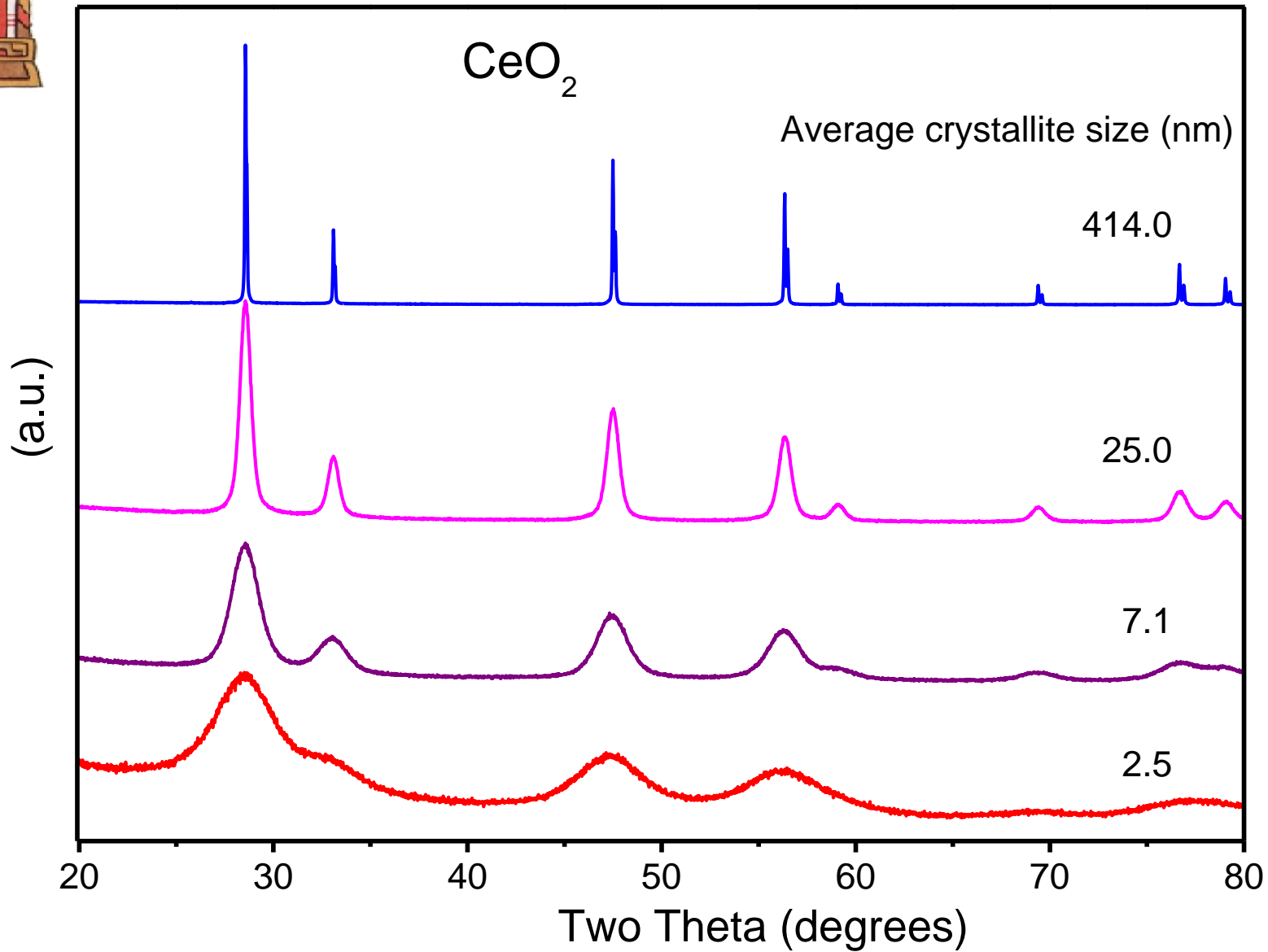




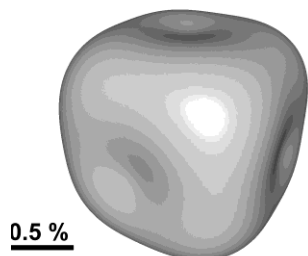
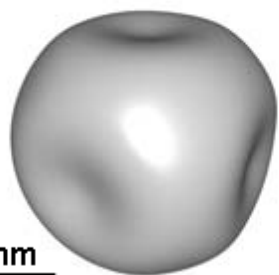
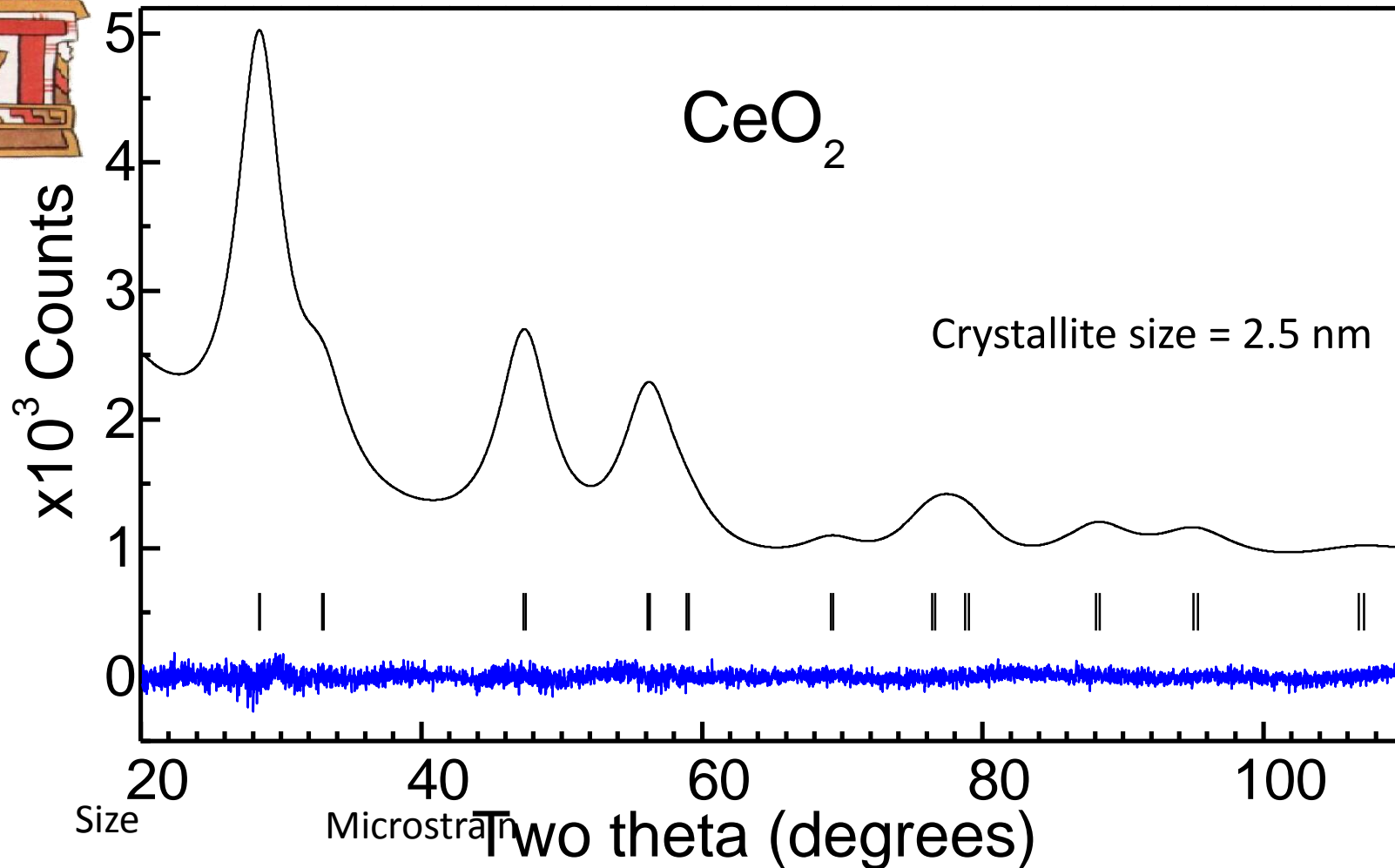
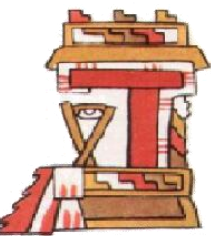
$$H_L = F_h(\alpha_z) / \cos \theta$$

$$F_h(\alpha_z) = \lambda \sum a_{\text{imp}} Y_{\text{imp}}(\theta, \Phi)$$



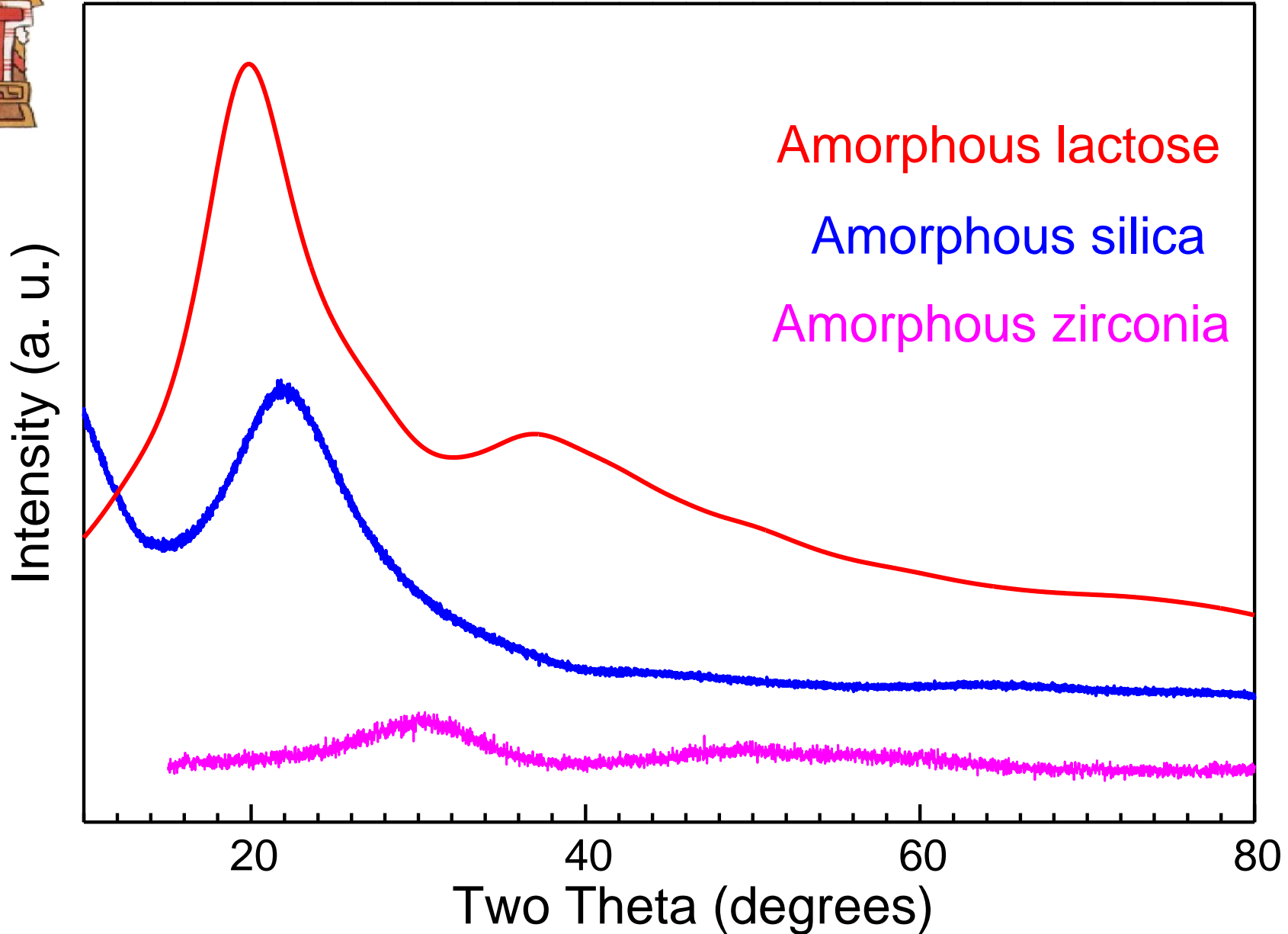


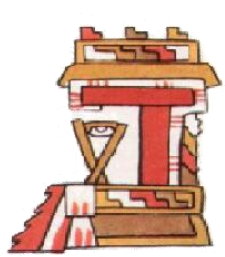
The Rietveld technique can be used to study nanocrystalline materials



Area nm ²	Volume nm ³	Specific Area m ² g ⁻¹	Number of atoms	Crystallites per gram
20.9	8.64	339	651	1.62 x 10 ¹⁹

Can the Rietveld technique be used to analyze amorphous materials?





Silicon oxide has several low temperature polymorphs:

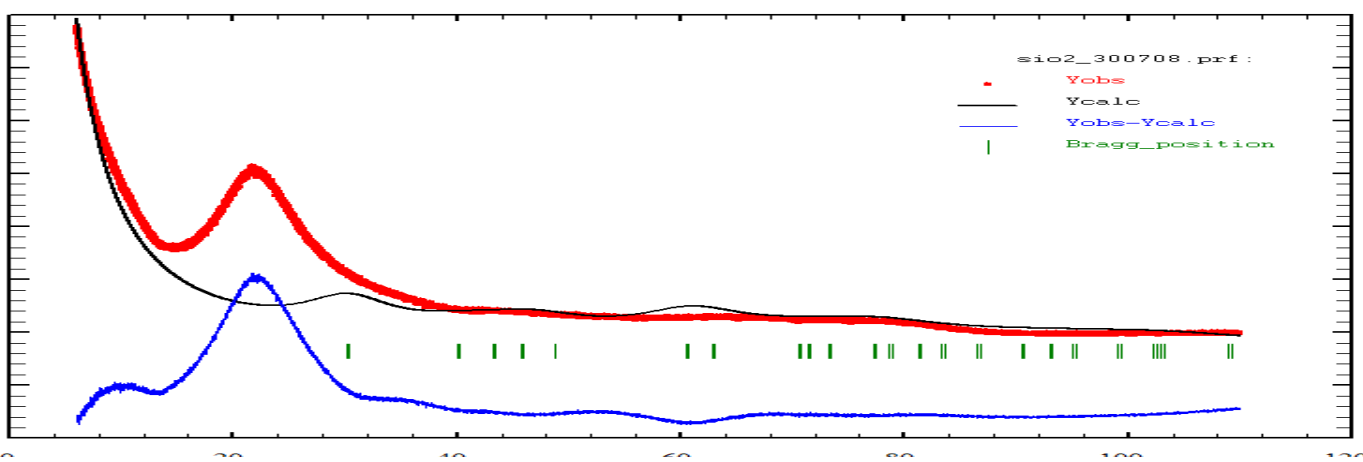
Stishovite, Tetragonal

Beta-Cristobalite, Cubic

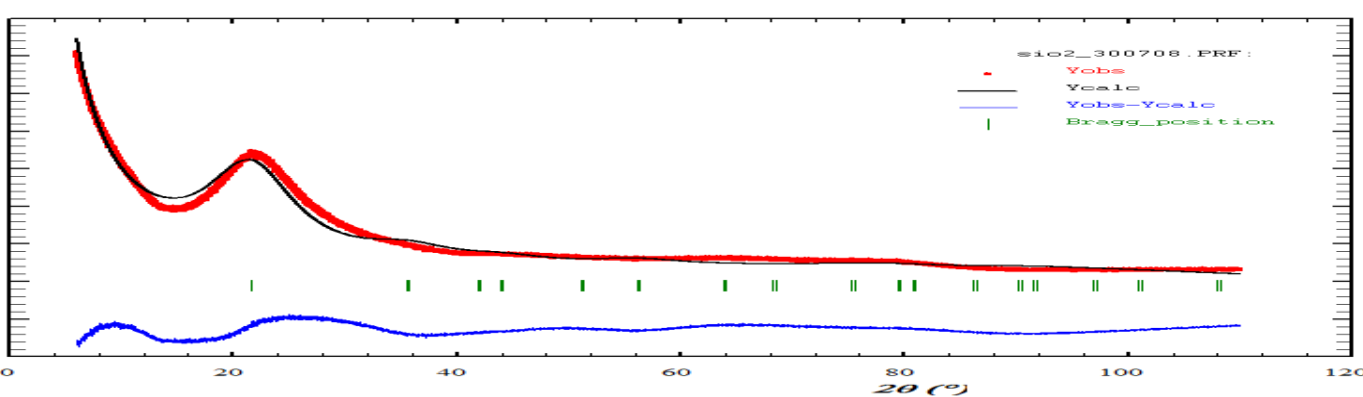
Alpha-Cristobalite, Tetragonal



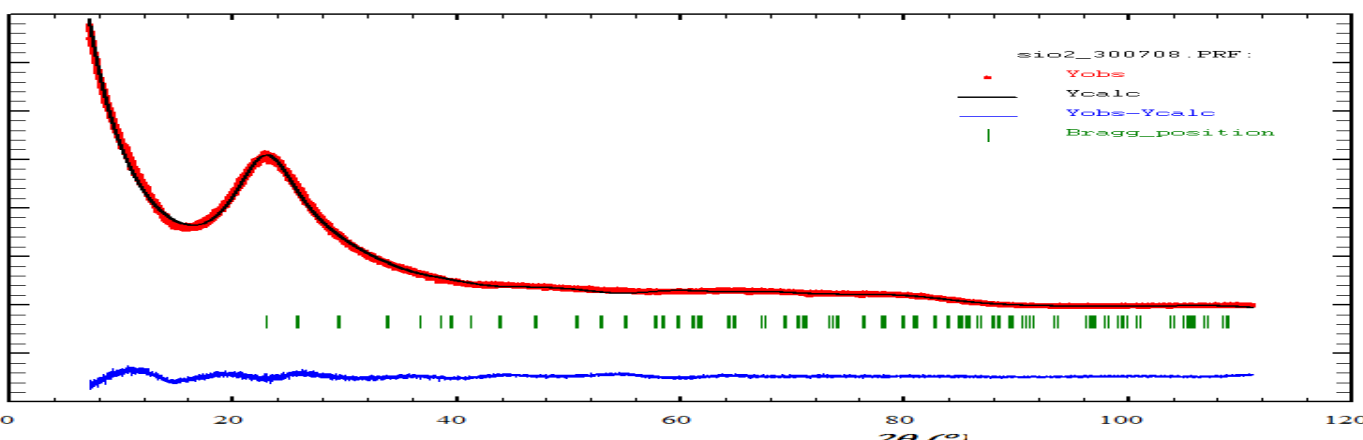
Intensity (arb)



Intensity (arb. units)



Intensity (arb. units)

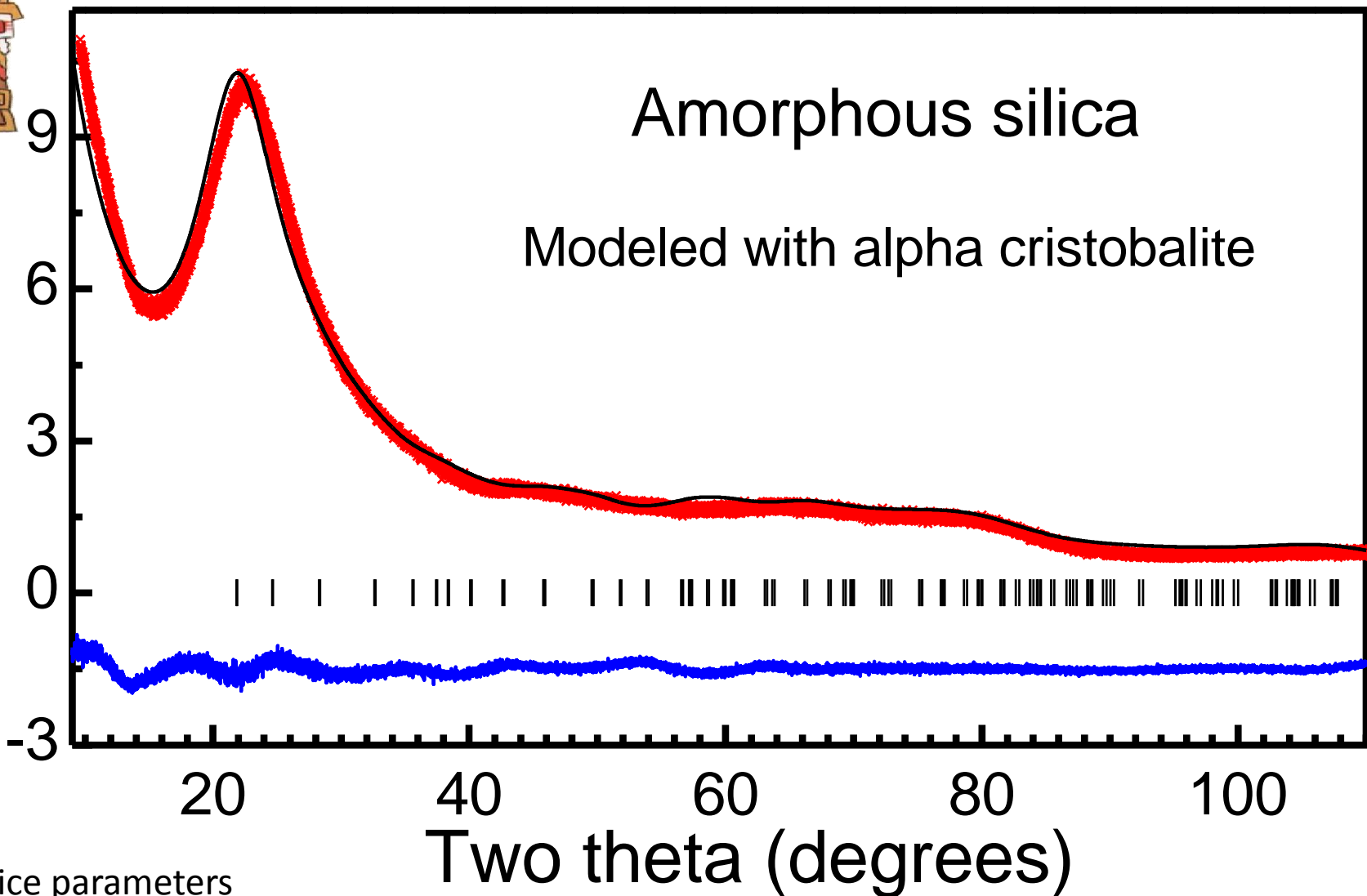




$\times 10^3$ Counts

Amorphous silica

Modeled with alpha cristobalite



Lattice parameters

$a = 0.4971$ nm

$c = 0.6928$ nm

$a = 0.4895(1)$ nm

$c = 0.6327(2)$ nm

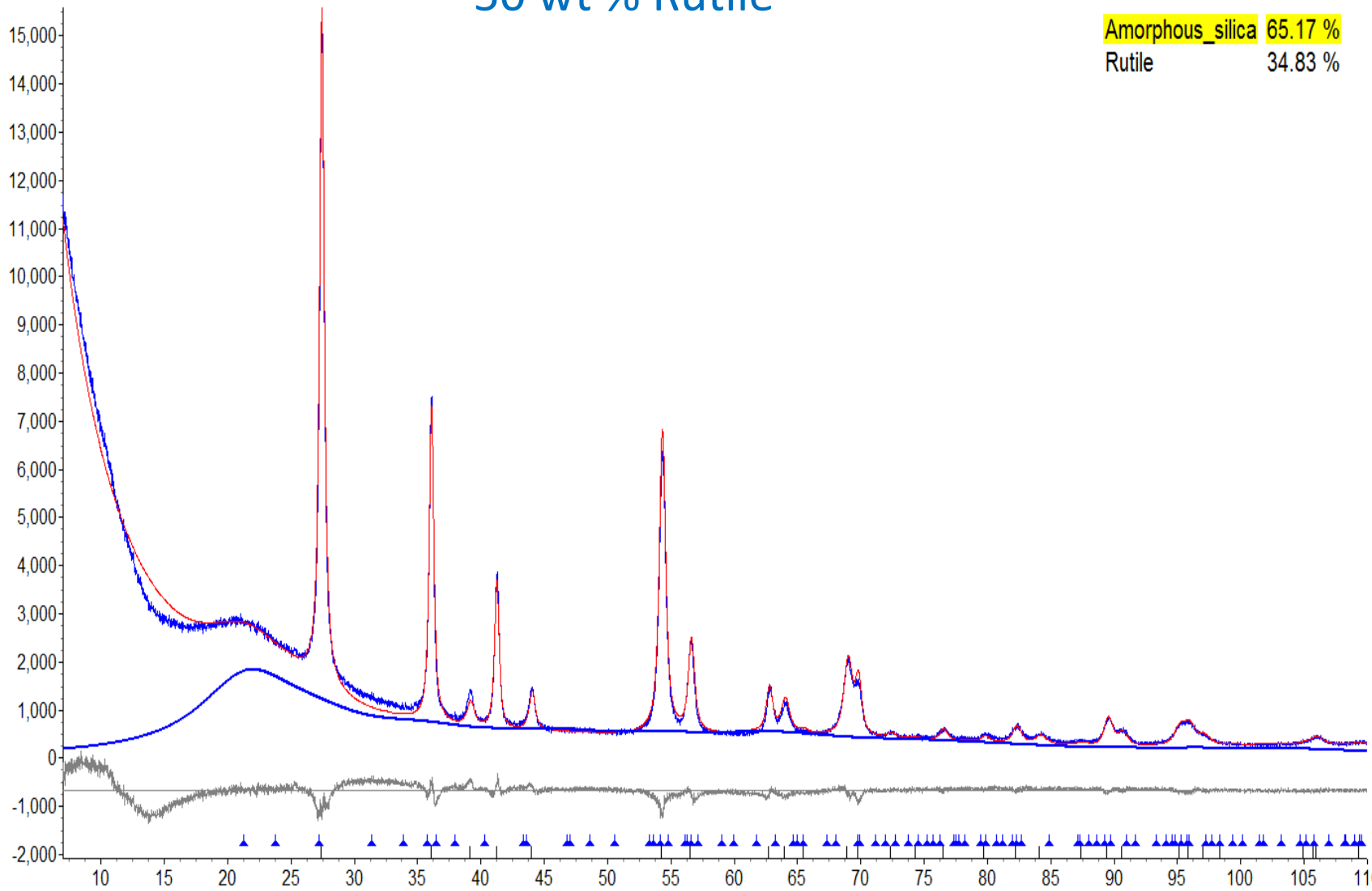
Average size 1.0 nm

Maximal microstrain 1.0 %



Nominal concentrations: 50 wt % Amorphous silica 50 wt % Rutile

Amorphous_silica	65.17 %
Rutile	34.83 %



$$y_{ci}(2\theta_i) = S \sum |F_K|^2 \phi(2\theta_i - 2\theta_K) L_K P_K A + y_{bi}$$

Improving Instrument modeling
or instrument optic

Background:

Simple model Chevychev Polynomial

It is necessary to take into account the
Inelastic Compton scattering



Crystallization of amorphous lactose

Lactose crystallizes in three polymorphs:

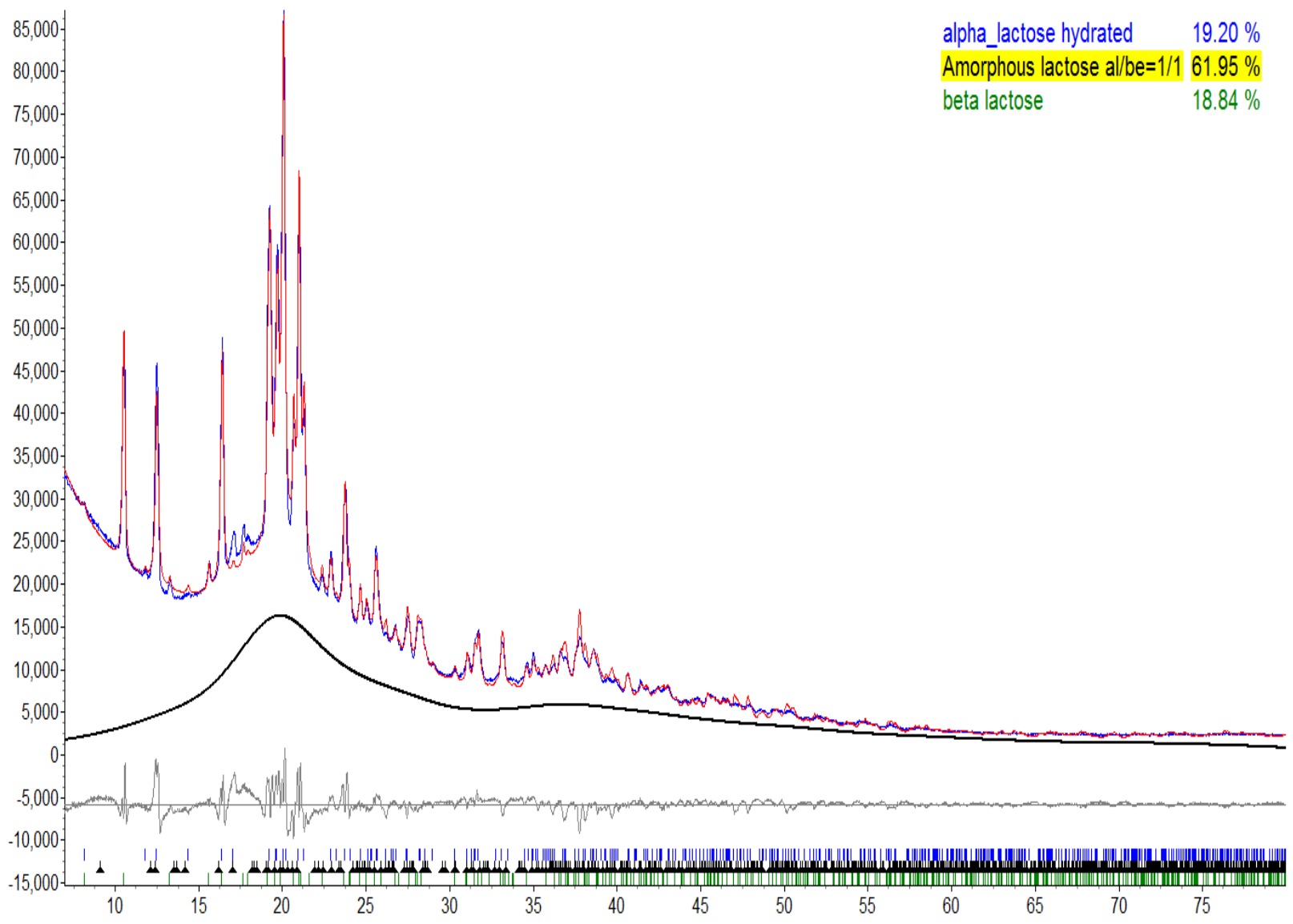
Alpha Lactose hydrated, Monoclinic

Beta Lactose, Monoclinic

1/1 Alpha/Beta phase, Triclinic

The Amorphous phase was modeled with the

Crystallography of the Triclinic phase





Amorphous Indomethacin:

Crystalline Alpha-Form

Crystalline Gamma-Form

From the NMR experiments:

The local atomic order of the amorphous Phase is similar to that in the Alpha-form



Conclusions

The Rietveld refinement technique can be used to obtain information about the concentrations of the phases in a sample inclusive when one of them is amorphous.

The amorphous phase should be modeled with the crystalline structure of the phase that crystallizes first.

The analysis requires to improve the model for the background and the optic of the diffractometer.



Some codes to refine crystalline structures

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